

**RELIABILITY DATA  
LT1011 / RH1011  
10/26/2003**

**• OPERATING LIFE TEST**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS <sup>(1)</sup> AT +125°C	NUMBER OF <sup>(2)</sup> FAILURES
CERDIP	157	9707	9738	168.13	0
FLATPAK/LCC	240	9206	9721	253.57	0
HERMETIC	1,031	8601	0245	1,588.10	0
PLASTIC DIP	139	9124	9336	312.12	0
	1,567			2,321.92	0

**• PRESSURE COOKER TEST AT 15 PSIG, +121°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
PLASTIC DIP	1,440	9124	0209	48.10	0
SOIC/SOT/MSOP	1,299	9322	0017	31.18	0
	2,739			79.28	0

**• TEMP CYCLE FROM -65°C to +150°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
CERDIP	318	9406	0234	103.33	0
FLATPAK/LCC	71	9206	9721	7.10	0
HERMETIC	136	8605	0245	13.60	0
PLASTIC DIP	240	9124	0209	30.30	0
SOIC/SOT/MSOP	101	9348	0017	10.10	0
	866			164.43	0

**• THERMAL SHOCK FROM -65°C to +150°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
CERDIP	345	9406	0234	98.03	0
FLATPAK/LCC	17	9721	9721	1.70	0
HERMETIC	66	8605	0245	2.44	0
PLASTIC DIP	230	9124	9810	32.43	0
SOIC/SOT/MSOP	147	9340	0017	14.70	0
	805			149.29	0

(1) Assumes Activation Energy = 1.0 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 0.79 FITS

(3) Mean Time Between Failures in Years = 144,401

Note: 1 FIT = 1 Failure in One Billion Hours.